Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination CHUNG ET AL.	
10/532,884		
Examiner	Art Unit	
Tu X. Nguyen	2618	

SEARCHED					
Class	Subclass	Date	Examiner		
455	67.1	5/18/2007	TN		
	456,427				
	67.4				
	423				
	12.1				
	3.02				
	67.11				
	134,135				
	13.2				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
455	12.1	5/18/2007	TN		
	135				
	13.2				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
DATE	EXMR			
5/18/2007	TN			
1				
	DATE			